

Notice of References Cited	Application/Control No. 10/509,409	Applicant(s)/Patent Under Reexamination HOELEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Web page http://en.wikipedia.org/wiki/Reflection_%28physics%29 "Reflection (physics)" from Wikipedia, the free encyclopedia, pp. 1-3. Undated.			
	V	Newly Revised and Updated Random House Webster's College Dictionary, pp. 1-2 Undated.			
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